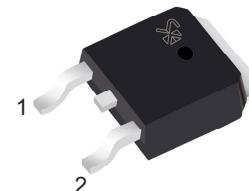
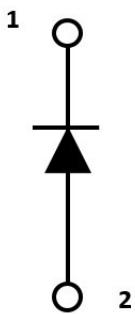


# Silicon Carbide Schottky Barrier Diode

**650V, 15A SiC SBD**

General Description		
The Q-SSC1565 uses a completely new technology and designs to provide superior switching performances and higher reliability. This device is suitable for use in power factor correction (PFC), switch mode power supplies (SMPS) and general purpose applications.		

Product Summary			TO-252
V <sub>RRM</sub>	650	V	
I <sub>F</sub> @ T <sub>C</sub> =127°C	15	A	
Q <sub>c</sub> @ VR=400V	37.9	nC	
E <sub>c</sub> @ VR=400V	9.36	μJ	
Features			Graphic Symbol
<ul style="list-style-type: none"> <li>Temperature independent switching behavior</li> <li>No reverse recovery current / No forward recovery</li> <li>Excellent thermal performances</li> <li>High surge current capability</li> </ul>			
Applications			
<ul style="list-style-type: none"> <li>Switch mode power supply</li> <li>Power factor correction</li> <li>Solar inverter</li> <li>Uninterruptible power supply</li> </ul>			

## Maximum Ratings (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Repetitive Peak Reverse Voltage	V <sub>RRM</sub>	650	V
Continuous Forward Current, D=1	T <sub>C</sub> =25°C	32.2	A
	T <sub>C</sub> =127°C	15	
Non-Repetitive Peak Forward Surge Current, Half Sine Wave, 10ms	T <sub>C</sub> =25°C	63	A
	T <sub>C</sub> =150°C	52	
i <sup>2</sup> t Value, 10ms	∫i <sup>2</sup> dt	19.8	A
Non-Repetitive Peak Forward Current, 10us	I <sub>F,max</sub>	378	A
Power Dissipation	P <sub>D</sub>	81.2	W
Storage Temperature Range	T <sub>STG</sub>	-55 to 150°C	°C
Operating Junction Temperature Range	T <sub>J</sub>	-55 to 175°C	°C

### Thermal Characteristics

Parameter	Symbol	Conditions	Min.	Typ	Max	Unit
Maximum Junction-to-Ambient <sup>1</sup>	R <sub>thJA</sub>	TO-252	-	1.02	1.84	°C/W
Maximum Junction-to-Case <sup>1</sup>	R <sub>thJC</sub>	TO-252	-	-	60	°C/W

### Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

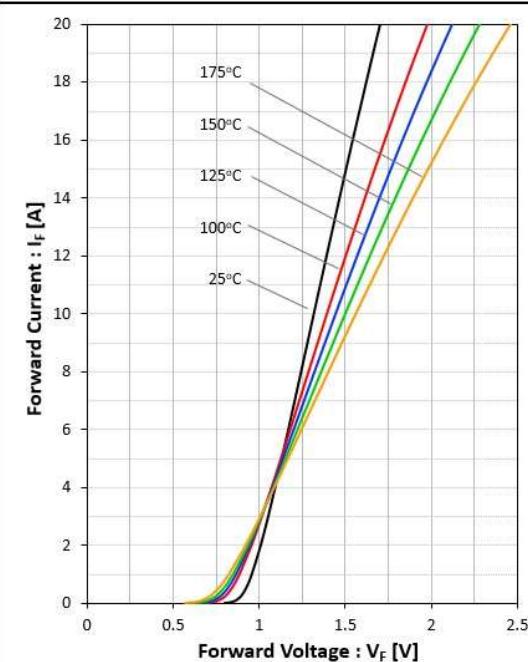
Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
<b>STATIC CHARACTERISTICS</b>						
DC Blocking Voltage	V <sub>R</sub>	I <sub>R</sub> =100uA, T <sub>j</sub> =25°C	650	-	-	V
		I <sub>R</sub> =100uA, T <sub>j</sub> =175°C	650	-	-	
Forward Voltage	V <sub>F</sub>	I <sub>F</sub> =10A, T <sub>j</sub> =25°C	-	1.4	1.7	V
		I <sub>F</sub> =10A, T <sub>j</sub> =150°C	-	1.8	2.2	
		I <sub>F</sub> =10A, T <sub>j</sub> =175°C	-	1.9	2.4	
Reverse Current	I <sub>R</sub>	V <sub>R</sub> =650V, T <sub>j</sub> =25°C	-	1.1	55	μA
		V <sub>R</sub> =650V, T <sub>j</sub> =150°C	-	11	110	
		V <sub>R</sub> =650V, T <sub>j</sub> =175°C	-	25	250	
<b>DYNAMIC CHARACTERISTICS</b>						
Total Capacitive Charge	Q <sub>C</sub>	V <sub>R</sub> =400V, T <sub>j</sub> =25°C $Q_C = \int_0^{V_R} C(V) dV$	-	37.9	-	nC
Total Capacitance	C	V <sub>R</sub> =0.1V, f=1MHz, T <sub>j</sub> =25°C	-	668	-	pF
		V <sub>R</sub> =200V, f=1MHz, T <sub>j</sub> =25°C	-	72.7	-	
		V <sub>R</sub> =400V, f=1MHz, T <sub>j</sub> =25°C	-	63.2	-	
Capacitance Stored Energy	E <sub>C</sub>	V <sub>R</sub> =400V, f=1MHz, T <sub>j</sub> =25°C	-	9.36	-	μJ

Notes:

1. Heat sink size: 25 x 17 x 4 cm<sup>3</sup>
2. Pulse Test: Pulse Width ≤300μs, Duty Cycle≤ 2%.
3. The power dissipation is limited by 175°C junction temperature.
4. The data is theoretically the same as I<sub>F</sub> and I<sub>FSM</sub> in real applications, should be limited by total power dissipation.

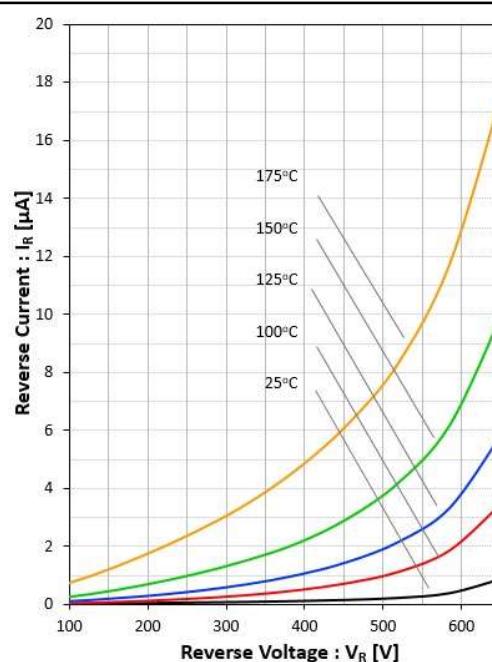
## Typical Operating Characteristics

Figure 1: Typical Forward Characteristics



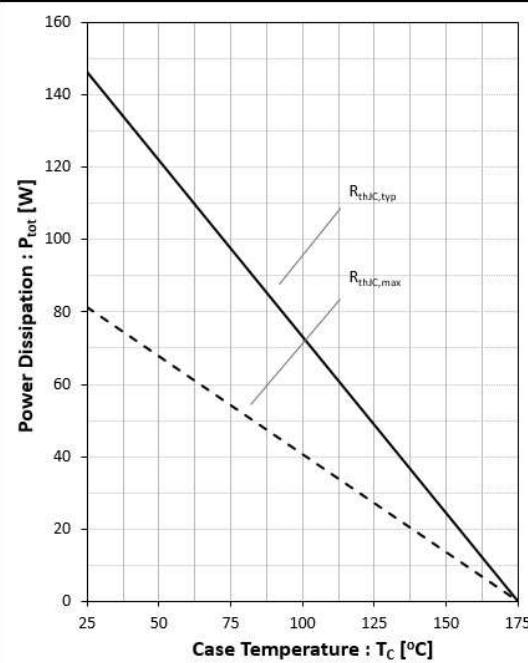
$$I_F = f(V_F, T_j)$$

Figure 2: Typical Reverse Characteristics



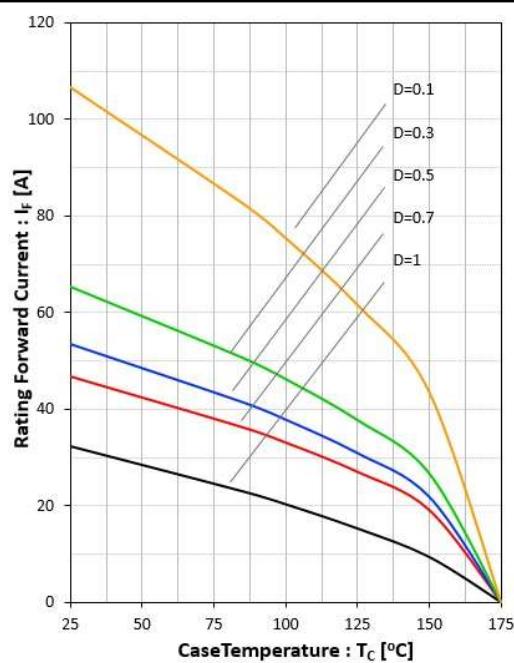
$$I_R = f(V_R, T_j)$$

Figure 3: Power Derating Curves

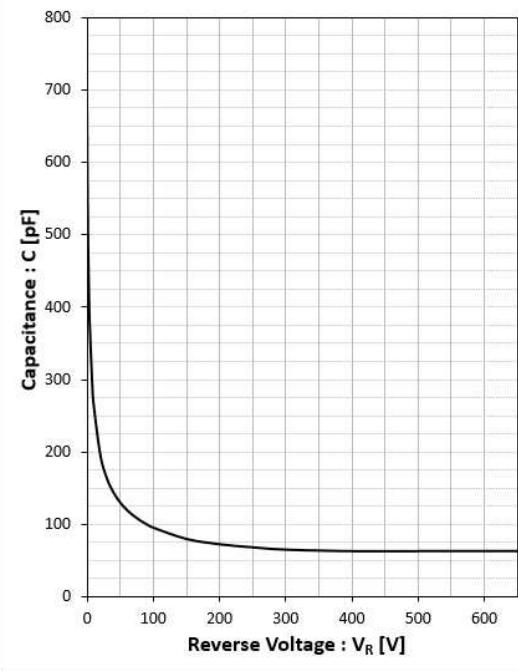
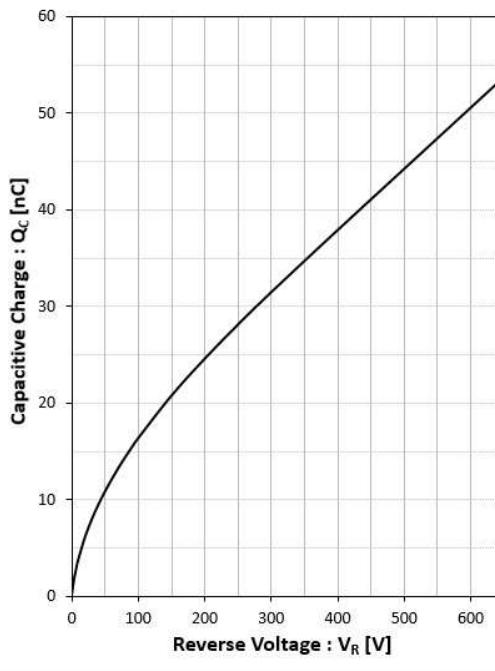
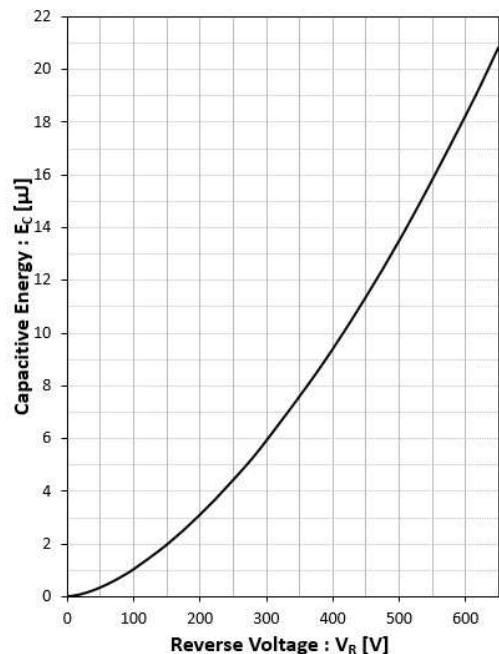
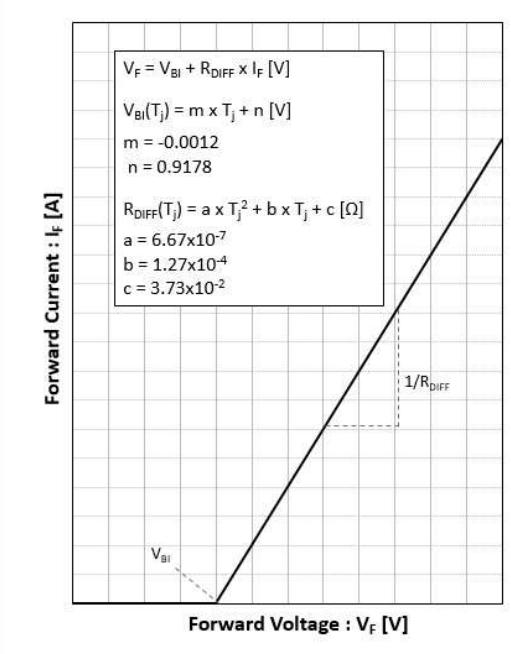


$$P_{tot} = f(T_C); T_j=175^\circ\text{C}$$

Figure 4: Current Derating Curves



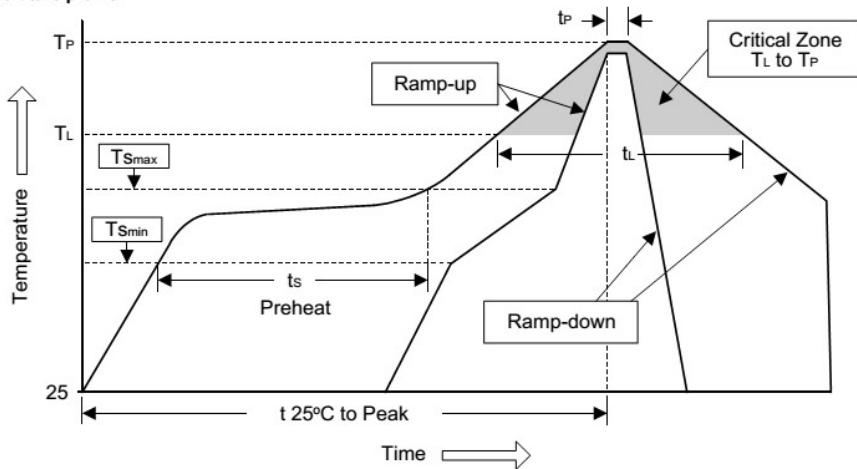
$$I_F = f(T_C); R_{thJC,max}; V_{F,max}; T_j \leq 175^\circ\text{C}; D = t_p/T$$

**Typical Operating Characteristics (Cont.)**
**Figure 5: Typical Junction Capacitance**

 $C = f(V_R); f=1\text{MHz}$ 
**Figure 6: Typical Capacitive Charge**

 $Q_C = f(V_R); f=1\text{MHz}$ 
**Figure 7: Typical Capacitive Energy**

 $E_C = f(V_R); f=1\text{MHz}$ 
**Figure 8: Forward Curve Model**

 $I_F = f(V_F, T_j)$

## Soldering Methods for CW Product

1. Storage environment: Temperature=10°C to35°C Humidity=65%±15%
2. Reflow soldering of surface-mount devices

Figure 1: Temperature profile



Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate ( $T_L$ to $T_p$ )	<3°C/sec	<3°C/sec
Preheat		
- Temperature Min ( $T_{Smin}$ )	100°C	150°C
- Temperature Max ( $T_{Smax}$ )	150°C	200°C
- Time (min to max) (ts)	60 to 120 sec	60 to 180 sec
$T_{Smax}$ to $T_L$	<3°C/sec	<3°C/sec
Time maintained above:		
- Temperature ( $T_L$ )	183°C	217°C
- Time ( $t_L$ )	60 to 150 sec	60 to 150 sec
Peak Temperature ( $T_p$ )	240°C +0/-5°C	260°C +0/-5°C
Time within 5°C of actual Peak Temperature ( $t_p$ )	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25°C to Peak Temperature	<6 minutes	<8 minutes

### 3. Flow (wave) soldering (solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices.	245°C ±5°C	5sec ±1sec
Pb-Free devices.	260°C +0/-5°C	5sec ±1sec